

Issue Classification	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/016,323	HEI ET AL.
Examiner	Art Unit	
David M. Naff	1651	

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)							
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
435		2		424	529						
INTERNATIONAL CLASSIFICATION				435	238	283.1					
A	0	1	N	1/02	530	412	413	415			
A	6	1	K	35/14							
C	1	2	N	7/06							
C	1	2	M	1/00							
C	0	7	K	1/00							
 				 David M. Naff							
(Assistant Examiner) (Date)				Total Claims Allowed: 45							
 Diane Williams 3-29-05 (Legal Instruments Examiner) (Date)				3/21/05 (Primary Examiner) (Date)							
						O.G. Print Claim(s)			O.G. Print Fig. None		
						1			None		

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	31	31	38	91	121	151
2	2	32	32	39	92	122	152
3	3	33	33	40	93	123	153
4	4	34	64	41	94	124	154
5	5	35	65	42	95	125	155
6	6	36	66	43	96	126	156
7	7	37	67	44	97	127	157
8	8	38	68	45	98	128	158
9	9	39	69	46	99	129	159
10	10	40	70	47	100	130	160
11	11	41	71	48	101	131	161
12	12	42	72	49	102	132	162
13	13	43	73	50	103	133	163
14	14	44	74	51	104	134	164
15	15	45	75	52	105	135	165
16	16	46	76	53	106	136	166
17	17	47	77	54	107	137	167
18	18	48	78	55	108	138	168
19	19	49	79	56	109	139	169
20	20	50	80	57	110	140	170
21	21	51	81	58	111	141	171
22	22	52	82	59	112	142	172
23	23	53	83	60	113	143	173
24	24	54	84	61	114	144	174
25	25	55	85	62	115	145	175
26	26	56	86	63	116	146	176
27	27	57	87	64	117	147	177
28	28	1	58	65	118	148	178
29	29	2	59	66	119	149	179
30	30		60	67	120	150	180